

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/751,024	JANG ET AL.	
Examiner		Art Unit		Page 1 of 1
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,561,945 B2	05-2003	Shattuck et al.	475/331
	B	US-6,702,711 B2	03-2004	Zelikov et al.	475/331
	C	US-5,827,147 A	10-1998	Stewart, Matthew M.	475/331
	D	US-5,593,360 A	01-1997	Ishida et al.	475/331
	E	US-5,470,286 A	11-1995	Fan, Changming	475/331
	F	US-6,609,993 B2	08-2003	Ohkubo et al.	475/331
	G	US-6,575,265 B2	06-2003	Richardson et al.	180/444
	H	US-6,422,971 B1	07-2002	Katou et al.	475/331
	I	US-5,382,203 A	01-1995	Bellman et al.	475/331
	J	US-3,667,324	06-1972	Laing, James Morrison	475/159
	K	US-2003/0181284 A1	09-2003	Chen, Tai-Shan	475/331
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000109907 A	04-2000	Japan	OKAMURA, TAKAMI	B22F 07/06
	O	JP 01111804 A	04-1989	Japan	SUDO et al.	B22F 07/06
	P	JP 2000087118 A	03-2000	Japan	OKAMURA, TAKASHI	B22F 07/08
	Q	EP 271416 A1	06-1988	European Patent	DEGUILLAUME, RENE	F16H 57/08
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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